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Waveguide type dielectric resonators - Part 1-5: General information and test conditions - Measurement method of conductivity at interface between conductor layer and dielectric substrate at microwave frequency

EESTI STANDARDI EESSÕNA

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See Eesti standard EVS-EN 61338-1-5:2015 sisaldab Euroopa standardi EN 61338-1-5:2015 ingliskeelset teksti.	This Estonian standard EVS-EN 61338-1-5:2015 consists of the English text of the European standard EN 61338-1-5:2015.
Standard on jõustunud sellekohase teate avaldamisega EVS Teatajas.	This standard has been endorsed with a notification published in the official bulletin of the Estonian Centre for Standardisation.
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English Version

Waveguide type dielectric resonators - Part 1-5: General information and test conditions - Measurement method of conductivity at interface between conductor layer and dielectric substrate at microwave frequency
(IEC 61338-1-5:2015)

Résonateurs diélectriques à modes guidés - Partie 1-5: Informations générales et conditions d'essais - Méthode de mesure de la conductivité au niveau de l'interface entre une couche conductrice et un substrat diélectrique fonctionnant aux hyperfréquences
(IEC 61338-1-5:2015)

Dielektrische Resonatoren vom Wellenleitertyp - Teil 1-5: Allgemeine Informationen und Prüfbedingungen - Messverfahren für die Leitfähigkeit an der Grenzfläche zwischen Leiterschicht und dielektrischem Träger im Mikrowellen-Frequenzbereich
(IEC 61338-1-5:2015)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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European foreword

The text of document 49/1089/CDV, future edition 1 of IEC 61338-1-5, prepared by IEC/TC 49 "Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 61338-1-5:2015.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2016-04-30
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2018-07-30

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61338-1-3	-	Waveguide type dielectric resonators -- Part 1-3: General information and test conditions - Measurement method of complex relative permittivity for dielectric resonator materials at microwave frequency	EN 61338-1-3	-
IEC 62252	-	Maritime navigation and radiocommunication equipment and systems - Radar for craft not in compliance with IMO SOLAS Chapter V - Performance requirements, methods of test and required test results	EN 62252	-

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INTRODUCTION

IEC 61338 consists of the following parts, under the general title *Waveguide type dielectric resonators*:

- Part 1: Generic specification
- Part 1-3: General information and test conditions – Measurement method of complex relative permittivity for dielectric resonator materials at microwave frequency
- Part 1-4: General information and test conditions – Measurement method of complex relative permittivity for dielectric resonator materials at millimeter-wave frequency
- Part 2: Guidelines for oscillator and filter applications
- Part 4: Sectional specification
- Part 4-1: Blank detail specification

The International Electrotechnical Commission (IEC) draws attention to the fact that it is claimed that compliance with this document may involve the use of a patent concerning:

- The use of a TE_{010} mode dielectric rod resonator for the interface resistance and the interface conductivity measurement, given in Clause 4;
- The use of a substrate/conductor/substrate layer structure, where a conductor is formed between two dielectric substrates, for the interface resistance and interface conductivity measurement, given in Clause 5.

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